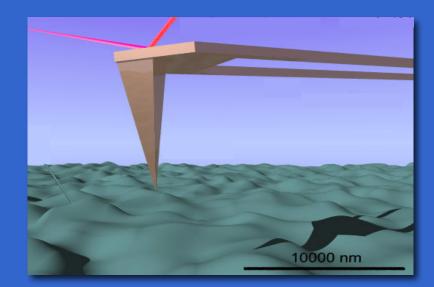
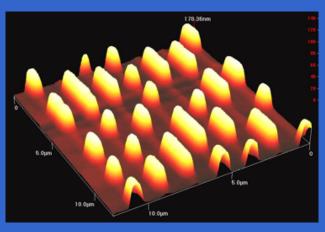
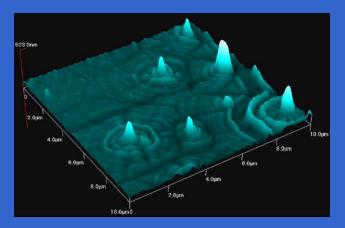
Get to the point!



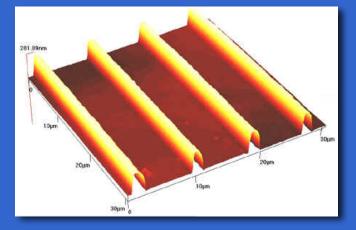
AFM - atomic force microscopy A 'new' view of structure (1986)



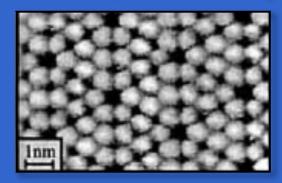
CD stamper



polymer growth



AlGaN/GaN quantum well waveguide



surface atoms on Si single crystal

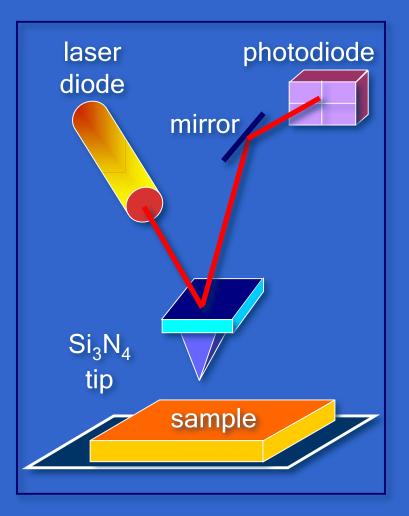
See Vocabulary of Surface Crystallography, Journal of Applied Physics 35, 1306 (1964), by Elizabeth A. Wood

AFM - atomic force microscopy

How does the microscope work?

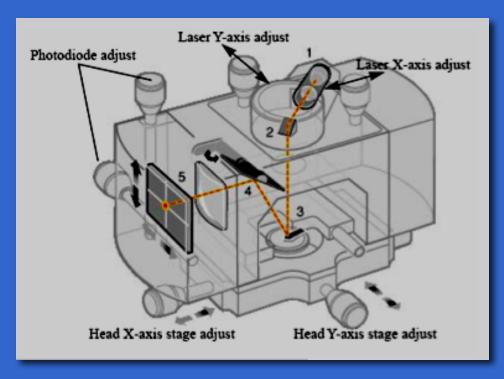
Tip scans sample

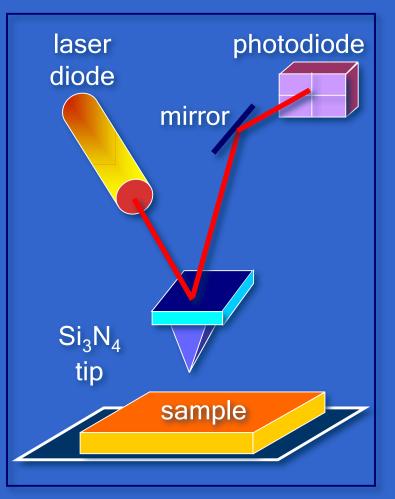
Up and down movement of tip recorded by position sensing photodiode



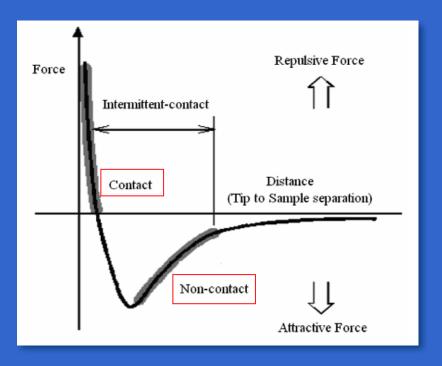
AFM - atomic force microscopy

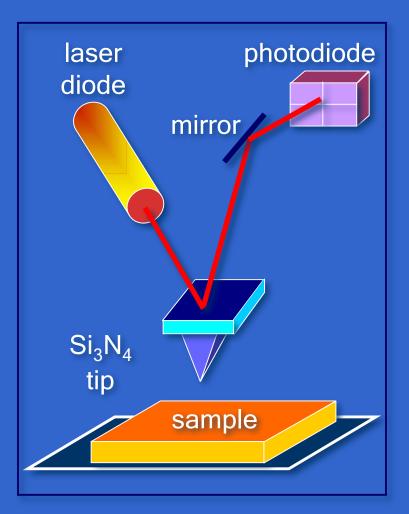
How does the microscope work?



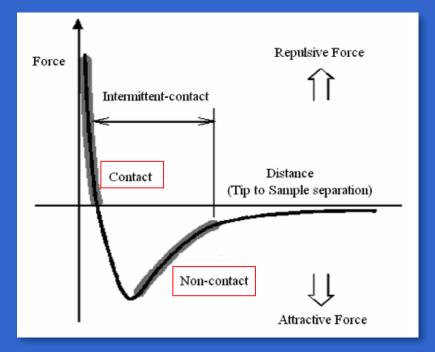


Two modes of operation

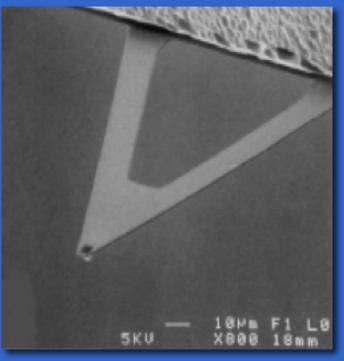




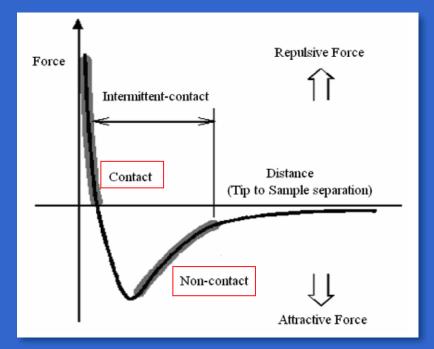
Contact mode - short-range interactions (Å) - interatomic forces



Tip: 5-20 nm radius, 10-25 μm high, on 50-400 μm cantilever beam



Contact mode - short-range interactions (Å) - interatomic forces



Detector system can measure deflections in nm range Tip: 5-20 nm radius, 10-25 μm high, on 50-400 μm cantilever beam

Cantilever: low stiffness can't deform surface

Tip contacts surface

Tip scans surface: either tip or specimen moved by piezoelectric positioning system over x and y

Contact mode - short-range interactions (Å) - interatomic forces

Two ways - 'constant force' feedback system moves tip in z direction to keep force constant

> 'constant height'..... no feedback system usually used when surface roughness small higher scan speeds possible

Tapping mode - long-range forces - van der Waals, electrostatic, magnetic

Tip vibrates (10⁵ Hz) close to specimen surface (50-150 Å) with amplitude 10-100 nm

May at times lightly contact surface

Suitable for soft materials

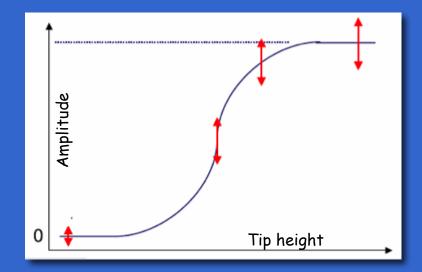


Tapping mode

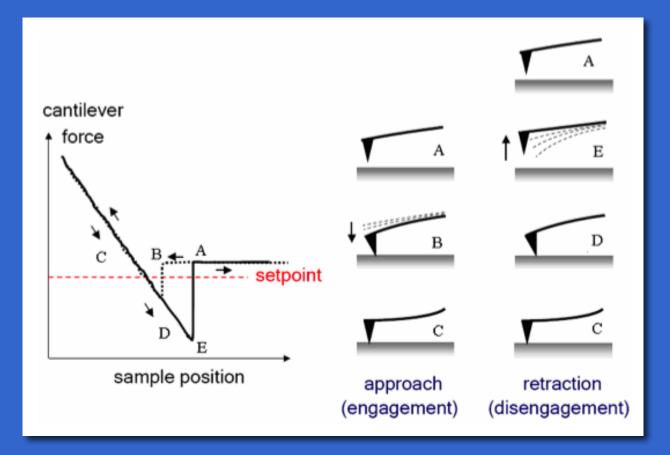
Tip vibrates (10⁵ Hz) close to specimen surface (50-150 Å) with amplitude 10-100 nm

May at times lightly contact surface

When near or on surface, oscillation is damped - tip z position corrected so that vibration amplitude stays constant



AFM - atomic force microscopy



From force-distance plot, can get: range & magnitude of attractive & repulsive forces elastic modulus & adhesion energy